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| Notice of References Cited | Application/Control No. 09/901,083 | Applicant(s)/Patent Under Reexamination HIGASHIDA, MOTOKI | |
| | Examiner Paul B. Yanchus | Art Unit 2116 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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|---|---|--|
| | U | "IEEE Standard Test Access Port and Boundary-Scan Architecture", 1993, Institute of Electrical and Electronics Engineers, Inc., pages 9-14 |
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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